Search Notes			
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Application/Control No.	Applicant(s)/Patent Reexamination	under
10/603,570	NAGASAKI, KOIC	н
Examiner	Art Unit	
Anthony Fick	1753	

	SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NO' (INCLUDING SEARCH)
	DATE	EXMR
See EAST search history	4/6/2006	ADF
Inventor search	4/5/2006	ADF
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Consulted with Alan Diamond and Jeffrey Barton	4/6/2006	ADF
Google scholar and IEEE database search for inventor and keywords	4/6/2006	ADF